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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Application Number	10/576,183
				Filing Date	December 22, 2006
				First Named Inventor	Peter Isberg
				Art Unit	1792
				Examiner Name	S. Ahmed
Sheet	1	of	1	Attorney Docket Number	43315-230171

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

FOREIGN PATENT DOCUMENTS					
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	CA	Michael W. Barsoum, The $M_{1-x}Al_x$ Phases: A New Class of Solids; Thermodynamically Stable Nanolaminates, <i>Prog Solid St Chem</i> , Vol. 28, pp. 201-281, 2000.			
	CB	Palmquist et al., Magnetron sputtered epitaxial single-phase Ti_3SiC_2 thin films, <i>Applied Physics Letters</i> , Vol. 81, No. 5, July 29, 2002.			
	CC	Seppänen et al., Structural Characterization of Epitaxial Ti_3SiC_2 Films, <i>Proceedings of the 53rd Annual Meeting of the Scandinavian Society for Electron Microscopy</i> , Tampere, Finland, 12-15 June 2002.			

Examiner Signature	Date Considered
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. * CITE NO.: Those application(s) which are marked with an asterisk (*) next to the Cite No. are not supplied (under 37 CFR 1.96(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. ¹ Applicant's unique citation designation number (optional). ² See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.